

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings of claims in the application:

Listing of Claims:

1-17. (Canceled)

18. (Currently amended) A method of classifying defects, comprising the steps of:

determining, ~~for each defect classification class of a first defect classifier for a first inspection machine, a~~ sampling rate of defects to be sampled and detected reviewed by a second inspection machine among defects detected ~~when an inspection sample is inspected by~~ [[the]] a first inspection machine; and

~~detecting, by reviewing with~~ said second inspection machine, defects sampled from said defects detected when a sample targeted for inspection is inspected by said first inspection machine~~[[,]]~~ in accordance with said determined sampling rate ~~for said each defect class; and classifying said detected~~ reviewed defects with a second defect classifier corresponding to said second inspection machine;

wherein the step of determining, said sampling rate is determined for each of defect classes classified by a first defect classifier corresponding to said first inspection machine, for each defect classification class of a first defect classifier corresponding to said first inspection machine, said rate of defects to be sampled and detected by said second inspection machine comprises the sub-steps of:

inspecting said inspection sample with said first inspection machine;

classifying defects of said inspection sample inspected and detected by the first inspection machine with said first defect classifier;

~~detecting defects of said inspection sample detected by said first inspection machine with a second inspection machine;~~

~~classify said defects of said inspection sample detected by the second defect inspection machine with said second defect classifier; and~~
~~determining, for said each defect classification class, said sampling rate for defects that are detected by said first inspection machine and classified by said first defect classifier in accordance with a relationship between the classification class of the defects in said inspection sample classified with said first defect classifier and the classification class of the defects in said inspection sample classified with said second defect classifier.~~

19. (Original) The method according to claim 18, wherein said second defect classifier has a decision tree for hierarchically expanding defect classification class elements via branch elements, and wherein said decision tree is such that a classification rule created with sample inspection information that has been previously derived from an inspection of an inspection sample is individually set for each of said branch elements.

20. (Currently amended) The method according to claim 19, wherein said individual classification rule that is set for each of said branch elements in said second defect classifier is set on a screen that displays said sample inspection information derived from said inspection of said inspection sample.

21. (Currently amended) A method of classifying defects, comprising the steps of:
determining a sampling rate of defects to be ~~sampled and detected~~ reviewed by a second inspection machine among defects detected by a first inspection machine; and
~~detecting reviewing~~, with said second inspection machine, defects sampled from said defects detected when a sample targeted for inspection is inspected by said first inspection machine[,]] in accordance with said determined sampling rate ~~for each defect class~~, and
classifying the ~~detected reviewed~~ defects with a second defect classifier corresponding to said second inspection machine;
wherein the step of determining, ~~determining said rate of defects to be sampled and detected by said second inspection machine comprises the sub-steps of:~~

12 inspecting an inspection sample with a first inspection machine;
13 classifying the defects inspected and detected by the first inspection
14 machine with a first defect classifier; and
15 determining a said sampling rate of defects sampled to be reviewed by
16 said second inspection machine is determined for each defect ~~classification~~ defect class in accordance
17 with reliability of ~~classification to each classification~~ defect class of defects classified with
18 ~~[[said]] a first defect classifier for said each defect classification class~~ corresponding to said first
19 inspection machine.

1 22. (Original) The method according to claim 21, wherein said second defect
2 classifier has a decision tree for hierarchically expanding defect classification class elements via
3 branch elements, and wherein said decision tree is such that a classification rule created with
4 sample inspection information that has been previously derived from an inspection of an
5 inspection sample is individually set for each of said branch elements.

1 23. (Currently amended) The method according to claim ~~[[19]]~~ 22, wherein
2 said classification rule that is individually set for each of said branch elements in said classifier is
3 set ~~[[from]]~~ on a screen that displays sample inspection information derived from an inspection
4 of said inspection sample.